Amendments to the Claims:

Please amend claims 1, 3, 5 and 9 as follows.

- 1. (Currently Amended) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic compound film containing an organic component as a main constituent by using a plasma derived from an etching gas containing an ammonia gas and a fluorine $\underline{F_2}$ gas as main constituents.
 - 2. The etching method of claim 1, wherein said etching gas contains an inert gas.
- 3. (Currently Amended) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as a main eonstituent by using a plasma derived from an etching gas containing a hydrogen \underline{H}_2 gas, a nitrogen \underline{N}_2 gas, and a fluorine \underline{F}_2 gas as main constituent, but no \underline{O}_2 gas.
- 4. (Original) The etching method of claim 3, wherein said etching gas contains an inert gas.
- 5. (Currently Amended) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main eonstituent by using a plasma derived from an etching gas containing a hydrogen \underline{H}_2 gas and a nitrogen trifluoride gas as main constituents, but no \underline{O}_2 gas.
- 6. (Original) The etching method of claim 5, wherein said etching gas contains an inert gas.
- 7. (Currently Amended) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main eonstituents by using a plasma derived from an etching gas containing a nitrogen N₂ gas and

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a hydrogen fluoride gas as main constituents.

- 8. (Original) The etching method of claim 7, wherein said etching gas contains an inert gas.
- 9. (Original) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main constituents by using a plasma derived from an etching gas containing a nitrogen H₂ gas and a fluorinated hydrocarbon gas as main constituents, but no O₂ gas.
- 10. (Original) The etching method of claim 9, wherein said etching gas contains an inert gas.
- 11. (Withdrawn) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main constituents by using a plasma derived from an etching gas containing a carbon dioxide gas and a fluorine gas as main constituents.
- 12. (Withdrawn) The etching method of claim 11, wherein said etching gas contains an inert gas.
- 13. (Withdrawn) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main constituents by using a plasma derived from an etching gas containing a carbon dioxide gas and a fluorinated hydrocarbon gas as main constituents.
- 14. (Withdrawn) The etching method of claim 13, wherein said etching gas contains an inert gas.
 - 15. (Withdrawn) An etching method comprising the step of performing

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anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main constituents by using a plasma derived from an etching gas containing a carbon monoxide gas and a fluorinated gas as main constituents.

- 16. (Withdrawn) The etching method of claim 15, wherein said etching gas contains an inert gas.
- 17. (Withdrawn) An etching method comprising the step of performing anisotropic etching with respect to an interlayer insulating film composed of an organic-inorganic hybrid film containing an organic component and a silica component as main constituents by using a plasma derived from an etching gas containing a carbon monoxide gas and a fluorinated gas as main constituents.
- 18. (Withdrawn) The etching method of claim 17, wherein said etching gas contains an inert gas.